

02.03.06

Express Mail No. EV 346 794 866 US  
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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: Fabrice LETERTRE et al.

Confirmation No. 9120

Application No.: 10/800,252

Group Art Unit: 1734

Filing Date: March 11, 2004

Examiner: M.A. Osele

For: METHODS FOR FORMING AN ASSEMBLY  
FOR TRANSFER OF A USEFUL LAYER

Atty. Docket No.: 4717-10400

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, Virginia 22313-1450

Sir:

Pursuant to applicants' duty of disclosure under 37 C.F.R. 1.56, enclosed is a PTO form 1449 (2 pages) which lists twenty-nine (29) references for the Examiner's review and consideration and copies of the . references are enclosed. It is respectfully requested that these references be made of record in this application by the Examiner's completion and return of the PTO Form 1449.

Pursuant to 37 CFR 126 1.17(p), a fee of \$180 is believed to be due for the filing of this statement as it is being submitted after the issuance of the first office action for this application. Please charge the required fee to Winston & Strawn LLP Deposit Account No. 50-1814.

Respectfully submitted,

Date: 2/1/06

  
Allan A. Fanucci (Reg. No. 30,256)

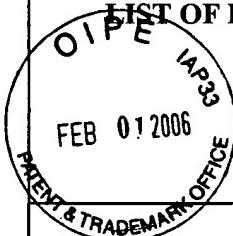
WINSTON & STRAWN LLP  
CUSTOMER NO. 28765  
(212) 294-3311

Enclosures

NY:1008698.1

02/06/2006 EFLORES 00000019 501814 10800252  
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<b>LIST OF REFERENCES CITED BY APPLICANT</b> <b>Form PTO-1449</b> <i>(Use several sheets if necessary)</i>				ATTY. DOCKET NO.:	APPLICATION NO.:	
				<b>4717-10400</b>	<b>10/800,252</b>	
				APPLICANT:		
				<b>Fabrice LETERTRE et al.</b>		
				FILING DATE:	GROUP:	
				<b>March 11, 2004</b>	<b>1734</b>	



Sheet 1 of 2

### U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	CITE NO.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	5,391,257	2/1995	Sullivan et al.	156	630	
	AB	5,863,830	1/1999	Bruel et al.	438	478	
	AC	6,287,891 B1	9/2001	Sayyah	438	106	
	AD	6,316,333 B1	11/2001	Bruel et al.	438	458	
	AE	6,335,258 B1	1/2002	Aspar et al.	438	406	
	AF	6,376,332 B1	4/2002	Yanagita et al.	438	458	
	AG	6,406,636 B1	6/2002	Vaganov	216	2	
	AH	6,448,155 B1	9/2002	Iwasaki et al.	438	464	
	AI	6,465,327 B1	10/2002	Aspar et al.	438	458	
	AJ	6,534,380 B1	3/2003	Yamauchi et al.	438	455	
	AK	6,548,338 B2	4/2003	Bernstein et al.	438	210	
	AL	6,562,648 B1	5/2003	Wong et al.	438	46	
	AM	6,673,694 B2	1/2004	Borenstein	438	411	
	AN	6,700,631B1	3/2004	Inoue et al.	349	45	
	AO	6,727,549 B1	4/2004	Doyke	257	347	
	AP	6,767,763 B1	7/2004	Uchiyama	438	116	
	AQ	6,809,009 B2	10/2004	Aspar et al.	438	459	
	AR	2002/0081822 A1	6/2002	Yanagita et al.	438	458	
	AS	2002/0096717 a1	7/2002	Chu et al.	257	347	
	AT	2003/0234075 A1	12/2003	Aspar et al.	156	344	

### FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AU	EP 0 106 566 B1	11/1989	Europe			X	
	AV	EP 0 977 252 A1	2/2000	Europe			X	
	AW	FR 2811807 with English Abstract	1/2002	France			X	
	AX	JP 10320851with English Abstract	12/1998	Japan			X	
	AY	JP 6229849with English Abstract	8/1994	Japan			X	
	AZ	JP 106052with English Abstract	5/1991	Japan			X	

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**FOREIGN PATENT DOCUMENTS**

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	BA	WO 02/05344 A1	1/2002	PCT			X	
	BB	WO 03/081664 A2	10/2003	PCT			X	

**NON-PATENT DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**

BC	S. Kodama et al., XP-000935156 "Variable Threshold AlGaAs/InGaAs Heterostructure Field-Effect Transistors with Paired Gated Gabricated Using the Wafer-Bonding Technique", Vol. 241ga, p. 434-435 (19099)

**EXAMINER****DATE CONSIDERED**

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.